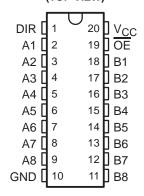
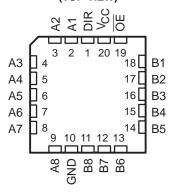
- EPIC[™] (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 2 V at V_{CC} = 3.3 V, T_A = 25°C
- Power Off Disables Outputs, Permitting Live Insertion
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Support Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V_{CC})
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Package, Ceramic Chip Carriers (FK), and DIPs (J)

SN54LVCH245A . . . J OR W PACKAGE SN74LVCH245A . . . DB, DW, OR PW PACKAGE (TOP VIEW)



SN54LVCH245A . . . FK PACKAGE (TOP VIEW)



description

The SN54LVCH245A octal bus transceiver is designed for 2.7-V to 3.6-V V_{CC} operation and the SN74LVCH245A octal bus transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

These devices are designed for asynchronous communication between data buses. These devices transmit data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so the buses are effectively isolated.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54LVCH245A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVCH245A is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

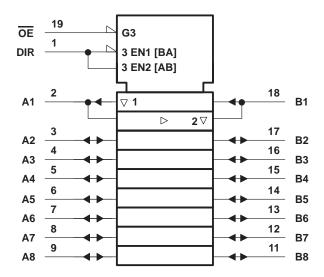
EPIC is a trademark of Texas Instruments Incorporated



FUNCTION TABLE

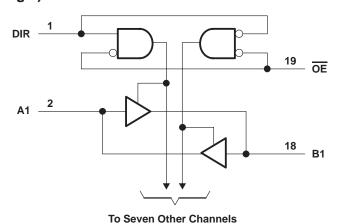
INP	UTS	OPERATION
OE	DIR	OPERATION
L	L	B data to A bus
L	Н	A data to B bus
Н	X	Isolation

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I : (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	\dots -0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O	
Continuous current through V _{CC} or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The value of V_{CC} is provided in the recommended operating conditions table.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			SN54L\	SN54LVCH245A		CH245A	LINUT	
			MIN	MAX	MIN	MAX	UNIT	
\/	Complete and	Operating	2	3.6	1.65	3.6	V	
VCC	Supply voltage	Data retention only	1.5		1.5		V	
		V _{CC} = 1.65 V to 1.95 V			0.65 × V _{CC}			
V_{IH}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$			1.7		V	
		V _{CC} = 2.7 V to 3.6 V	2		2			
		V _{CC} = 1.65 V to 1.95 V				0.35 × V _{CC}		
V_{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V				0.7	V	
		V _{CC} = 2.7 V to 3.6 V		0.8		0.8		
٧ı	Input voltage		0	5.5	0	5.5	V	
\/-	Output voltage	High or low state	0	Vcc	0	Vcc	V	
VO		3 state	0	5.5	0	5.5		
		V _{CC} = 1.65 V				-4		
1	High-level output current	V _{CC} = 2.3 V				-8	mA	
ЮН		V _{CC} = 2.7 V		-12		-12		
		VCC = 3 V		-24		-24		
		V _{CC} = 1.65 V				4		
lOL	Love lovel output ourrent	V _{CC} = 2.3 V				8	mA	
	Low-level output current	V _{CC} = 2.7 V		12		12		
		VCC = 3 V		24		24		
Δt/Δν	Input transition rise or fall rate		0	10	0	10	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN54LVCH245A, SN74LVCH245A OCTAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

SCES008F - JULY 1995 - REVISED JUNE 1998

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	1	SN54	LVCH245	iΑ	SN74I	LVCH245	A	UNIT	
		TEST CONDITIONS	VCC	MIN	TYP†	MAX	MIN	TYP [†]	MAX	UNII	
		100	1.65 V to 3.6 V				V _{CC} -0.2				
		I _{OH} = -100 μA	2.7 V to 3.6 V	V _{CC} -0.2							
		I _{OH} = -4 mA	1.65 V				1.2			V	
Vон		IOH = -8 mA	2.3 V				1.7				
		I _{OH} = -12 mA	2.7 V	2.2			2.2				
		IOH = -12 MA	3 V	2.4			2.4				
		I _{OH} = -24 mA	3 V	2.2			2.2				
		I _{OL} = 100 μA	1.65 V to 3.6 V						0.2		
		ΙΟΕ = 100 μΑ	2.7 V to 3.6 V			0.2					
V/o		I _{OL} = 4 mA	1.65 V						0.45	V	
VOL		I _{OL} = 8 mA	2.3 V						0.7	V	
		I _{OL} = 12 mA	2.7 V			0.4			0.4		
		I _{OL} = 24 mA	3 V			0.55			0.55		
II	Control inputs	V _I = 0 to 5.5 V	3.6 V			±5			±5	μΑ	
l _{off}		V _I or V _O = 5.5 V	0		-			-	±10	μΑ	
		V _I = 0.58 V	4.05.1/				‡				
		V _I = 1.07 V	1.65 V				‡				
		V _I = 0.7 V	0.01/				45				
I _I (hold)		V _I = 1.7 V	2.3 V				-45			μΑ	
ì		V _I = 0.8 V	2.1/	75			75			1	
		V _I = 2 V	3 V	-75			-75				
		V _I = 0 to 3.6 V§	36 V			±500			±500		
loz¶		V _O = 0 to 5.5 V	3.6 V			±15			±10	μА	
		V _I = V _{CC} or GND	0.004			10			10		
ICC		3.6 V ≤ V _I ≤ 5.5 V [#] I _O =	0 3.6 V			10			10	μΑ	
ΔICC		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	2.7 V to 3.6 V			500			500	μА	
Ci	Control inputs	$V_I = V_{CC}$ or GND	3.3 V		4	12		4		pF	
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	3.3 V		5.5	12		5.5		pF	

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[‡] This information was not available at the time of publication.

[§] This is the bus-hold maximum dynamic current required to switch the input from one state to another.

[¶] For I/O ports, the parameter IOZ includes the input leakage current.

[#] This applies in the disabled state only.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

			SN54LV			
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 2.7 V	V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN MAX	MIN	MAX	
^t pd	A or B	B or A	8	1	7	ns
^t en	ŌĒ	A or B	9.5	1	8.5	ns
t _{dis}	ŌĒ	A or B	8.5	1	7.5	ns

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			SN74LVCH245A								
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} =		V _{CC} =		VCC =	2.7 V	V _{CC} =	3.3 V 3 V	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
^t pd	A or B	B or A	†	†	†	†		7.3	1.5	6.3	ns
t _{en}	ŌE	A or B	†	†	†	†		9.5	1.5	8.5	ns
^t dis	ŌE	A or B	†	†	†	†		8.5	1.7	7.5	ns
t _{sk(o)} ‡										1	ns

[†] This information was not available at the time of publication.

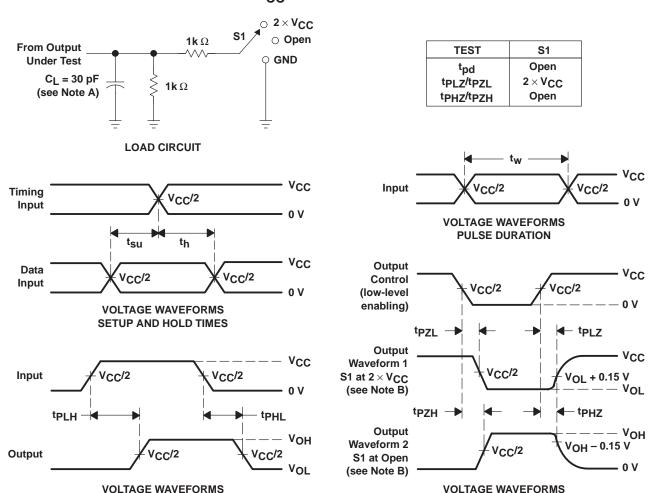
operating characteristics, T_A = 25°C

PARAMETER			TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT	
				TYP	TYP	TYP		
Card	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	47	pF	
C _{pd}	per transceiver	Outputs disabled		†	†	2	PF	

[†] This information was not available at the time of publication.

[‡] Skew between any two outputs of the same package switching in the same direction

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 V \pm 0.15 V$



NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

ENABLE AND DISABLE TIMES

- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r \leq$ 2 ns. $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- tpLZ and tpHZ are the same as tdis.

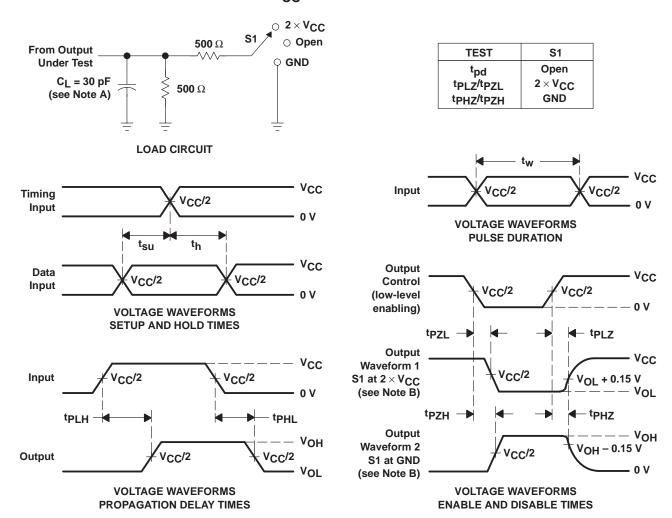
PROPAGATION DELAY TIMES

- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$

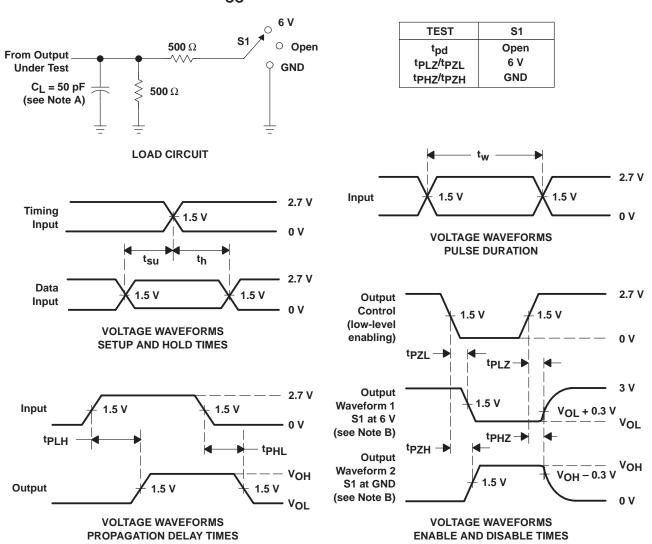


NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.7 V AND 3.3 V \pm 0.3 V



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z $_{O}$ = 50 Ω , $t_{r}\leq$ 2.5 ns, $t_{f}\leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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